

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
CHAE ET AL.

Examiner

LAUREN NGUYEN

Art Unit

2871

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0029054	10-2001	Maeda et al.	438/17
	B	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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